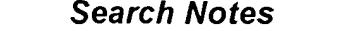


<b>Search Notes</b> 	<b>Application/Control No.</b>	<b>Applicant(s)/Patent under Reexamination</b>	
	10/621,970	GRAF ET AL.	
	<b>Examiner</b>	<b>Art Unit</b>	
	Mark K. Han	3767	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner